



2024 IEDM Conference Theme
**Shaping Tomorrow's
Semiconductor Technology**



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2024 IEEE International Electron Devices Meeting

December 7-11, 2024

*Hilton San Francisco Union Square
San Francisco, California*

IEDM is pleased to announce increased
technical focus in the area of:

Reliability of Systems and Devices (RSD)

Topics

Papers are solicited in the following themes of interest:

- Component level of FEOL/MEOL/BEOL characterization and reliability modeling
- Robustness and security of electronic circuits and systems
- Reliability of conventional and emerging memories
- Circuits, systems-level reliability, and aging
- Thermal and PID/charging management in existing and novel process integration
- Reliability of RF/mm-wave/5G in high-frequency applications
- Reliability of devices, circuits, and systems for more-than-Moore applications, automotive, aerospace and bio-applications (BioFETs, DNA detection, etc.)
- Reliability of cryogenic devices for future quantum computing applications

New or trending areas include:

- Reliability of new materials and/or new architectures for transistors
- Reliability of advanced 2.5D/3D IC advanced package
- Design for testing (DFT) / Design for reliability (DFR) solutions for improved reliability

Paper Submission

Submission deadline: July 11th

Single submission of final, four-page paper